

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10650518	MATTHEWS, KRISTINE E.
	Examiner	Art Unit
	Bayat, Ali	2624

SEARCHED

Class	Subclass	Date	Examiner
382	167,162,165,166,168,169,172,274	3/27/07	A.B
358	518-523	3/27/07	A.B
348	453	3/27/07	A.B
345	589,590,591,593,600,601	3/27/07	A.B

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with Phuoc Tran; EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM-TDB); Inventor name searched; IEEE Xplore; See text search history print out.	3/28/077	A.B

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
USPGPUB	See Interference search history print out.	3/27/07	A.B